



Contribution ID: 114

Type: **Contributed Poster**

Laser Tests Of Silicon Strip Detectors

Thursday 15 September 2005 10:30 (30 minutes)

This presentation collects experiences from tests of ATLAS end cap SCT modules using infrared semiconductor laser on 1060 nm wavelength. Sophisticated method of focusing was developed. Timing and interstrip properties of modules were measured.

Tests of silicon sensors simulate real experimental conditions and check important detector properties. Laser tests have good time and space description, but photons generate electron-hole pairs in silicon bulk via different mechanism. Detailed discussion about usability of laser test for particle detectors is presented.

Laser tests are extremely useful for tuning individual sensor and readout settings to find optimal working parameters. Furthermore they are good for comparison between the same type of detectors with exactly the same top surface properties.

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Session Classification: P : Coffee and Poster Session

Track Classification: Pixel Detectors for Charged Particles